



Education

Introducing and Validating SNIA SSS Performance Test Suite

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➤ SSS Performance Benchmarking Learning Objectives

- ◆ Get a good understanding of the various parameters that influence the performance characteristics of SSDs
- ◆ Get a full understanding of the proposed SNIA Performance Measurement Specification
- ◆ Provide step-by-step guidance on how to set up a test benchmark that enables comparison among the various SSS devices

Definition of SSS

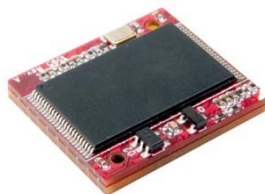
SSS = Solid State Storage



Traditional hard disk drive



Solid state hard drive



Flashy fists fly as OCZ and DDRdrive row over SSD performance



"dirty tricks used to drastically inflate IOPS results"...

" the egregious disparity between promised performance and reality"...

"This really isn't an 'apples to apples' comparison"...

"you can't use an X1 dragster on the open road but you can use a Ferrari Vertex 2 EX"...

http://www.theregister.co.uk/2011/01/14/ocz_and_ddrdrive_performance_row/

The Performance Landscape

One Year Later

- Read and Write IOPS Specifications (Iometer® Queue Depth 32)
 - Random 4 KB Reads: Up to 35 K IOPS
 - 80 GB - Up to 5.5 K IOPS
 - 160 GB - Up to 8.6 K IOPS
- Bandwidth Performance Specifications
 - Sustained Sequential Read: Up to 250 MB/s
 - Sustained Sequential Write:
 - 80 GB - Up to 70 MB/s
 - 160 GB - Up to 100 MB/s

MB/s or MB/s?

Performance

Average Access Time	20-120 microseconds
Sustained Read Throughput	250 MB/sec
Sustained Write Throughput	115 MB/sec
Random IOPS Read Operations	45,000 IO/sec, sustained
Random IOPS Write Operations	16,000 IO/sec, sustained

IOPS?

Block Size?

Prominent product specifications include:

- Up to 52,000 Sustained Random Read IOPS
- Up to 17,000 Sustained Random Write IOPS

PEAK sustained IOPS - Sector 4KB aligned (random preconditioned, Sustained speed)		
4KB random READ	50K / 50K	50K / 32K
4KB random WRITE	50K / 50K	50K / 11K
8KB random READ	23K / 23K	23K / 23K
8KB random WRITE	28K / 28K	28K / 11K

Random Precondition
Sustained Speed?

Sequential read	Up to 250 MB/sec
Sequential write	170 MB/sec

Random or Sustained?

Up to?

PERFORMANCE	
Sustained data transfer rate	240,000Mb/s
I/O data transfer rate	300MB/s

Client SSD



- Low cost
- C-MLC
- 0-7% over provisioning
- No backup power circuit
- No Enterprise features
- No customization
- Warranty 1-3 yrs

Enterprise SSD

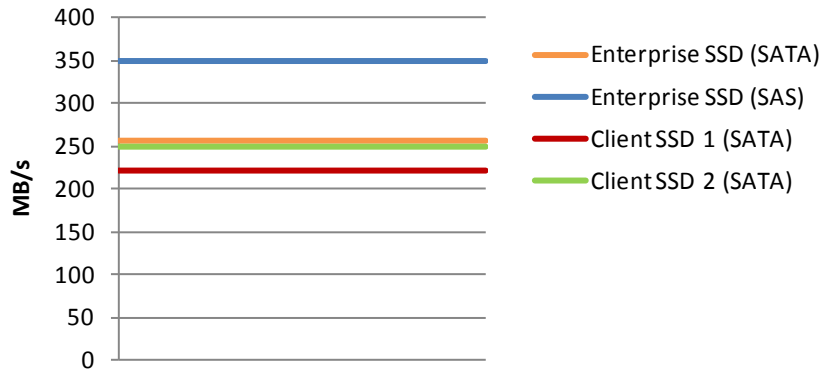


- Higher cost
- E-MLC/SLC
- 28-50% over provisioning
- Backup power circuit
- Enterprise features
- Customization
- Warranty 5 yrs

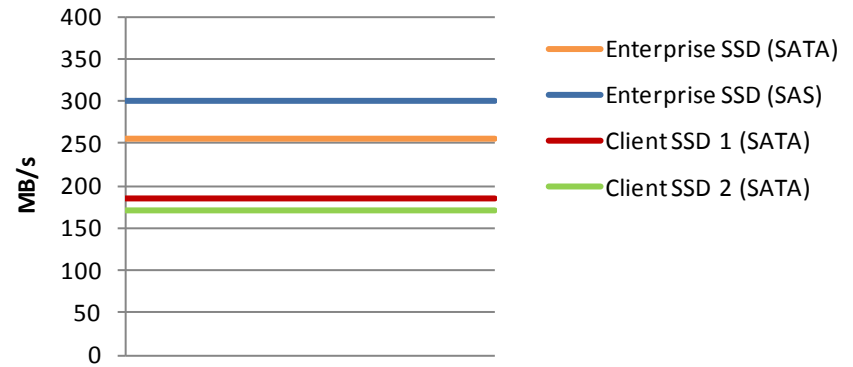
Performance Comparison

Enterprise vs. Client SSD

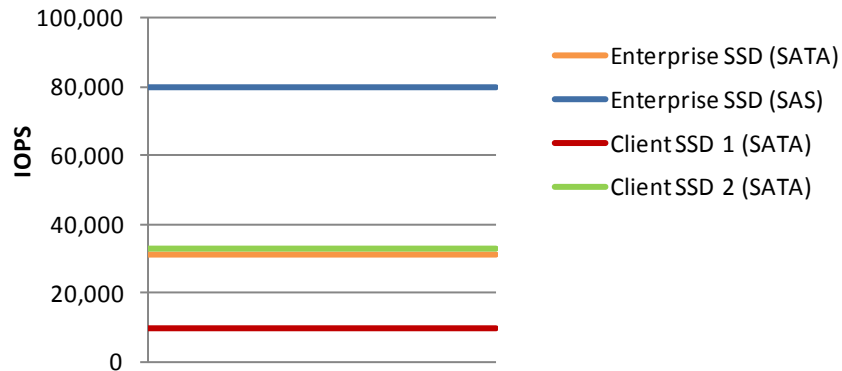
Sequential Read



Sequential Write



Random Read



Random Write



Variables influencing Performance

- Platform
 - Test Hardware (CPU, interface, chipset, etc)
 - Software (OS, drivers)
- SSS Device Architecture
 - Flash geometry, cache, flash management algorithm, etc

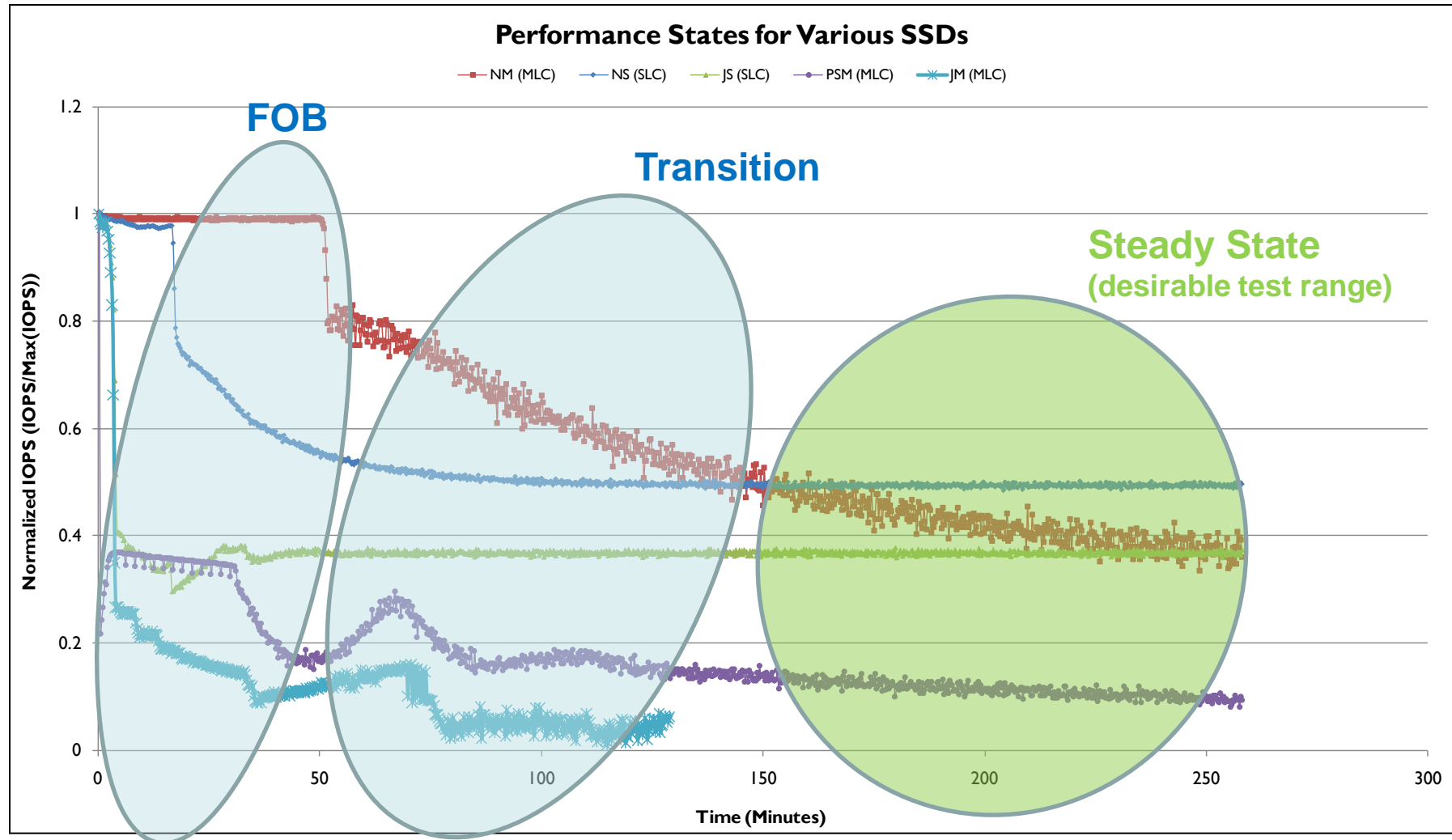


Variables influencing Performance

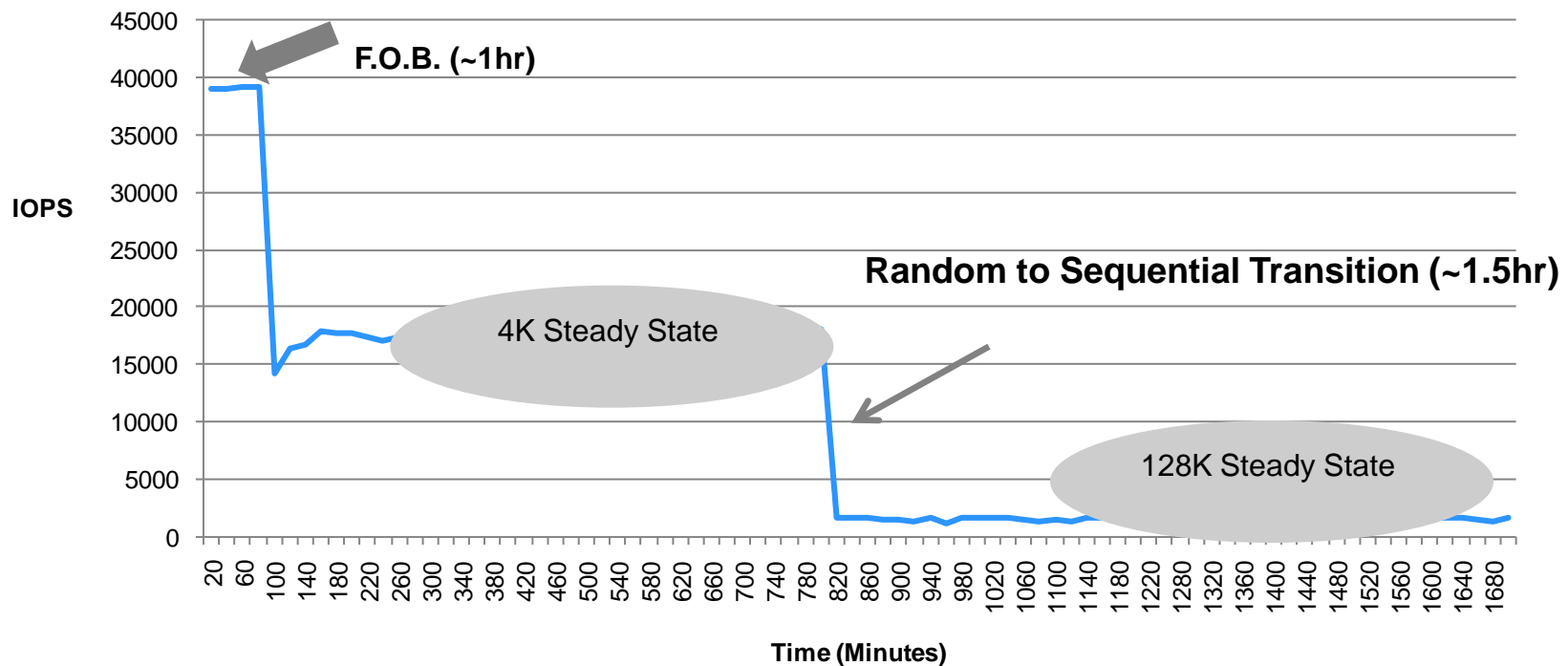
- Platform
 - Test Hardware (CPU, interface, chipset, etc)
 - Software (OS, drivers)
- SSS Device Architecture
 - Flash geometry, cache, flash management algorithm, etc
- Workload
 1. Write history & preconditioning: State of device before testing



The need for Preconditioning

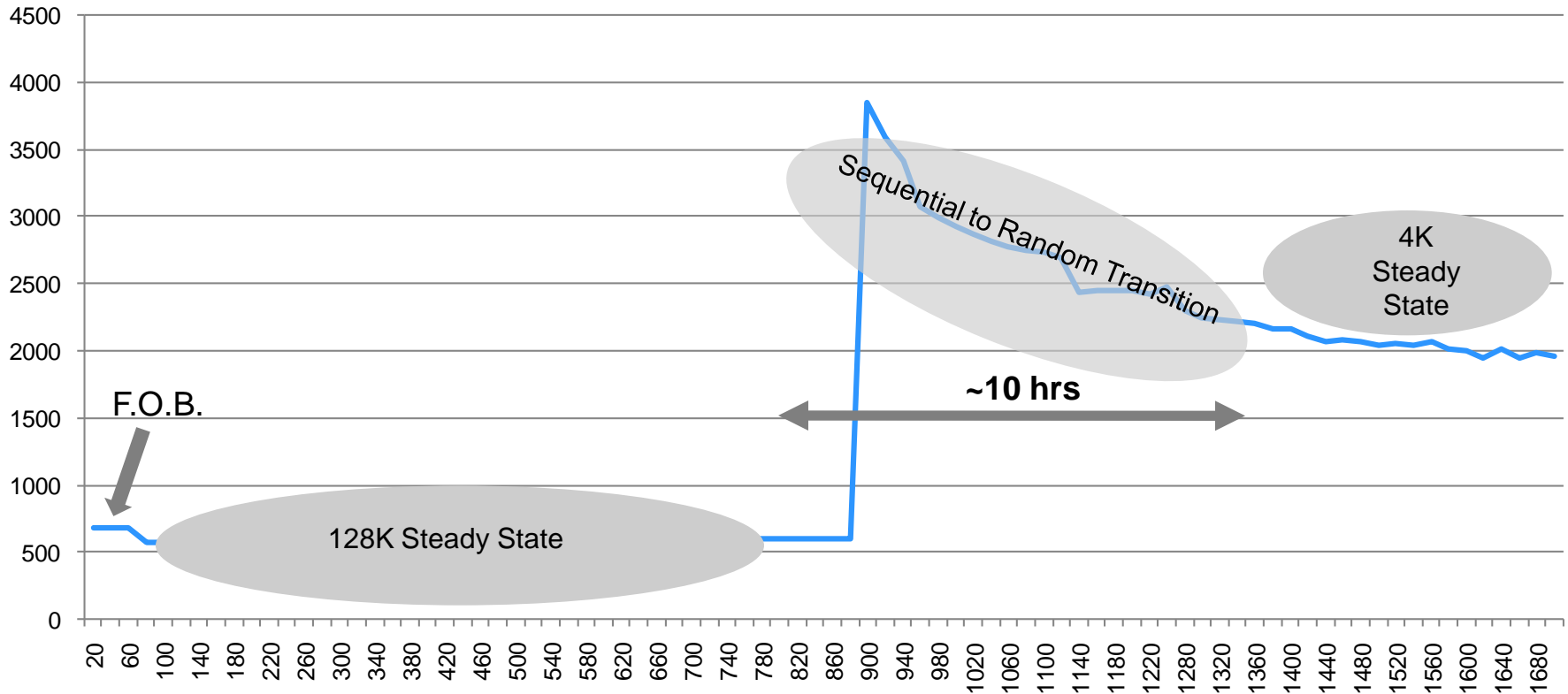


4K Random to 128K Sequential Transition



Write History - 2

128K Sequential to 4K Random Transition

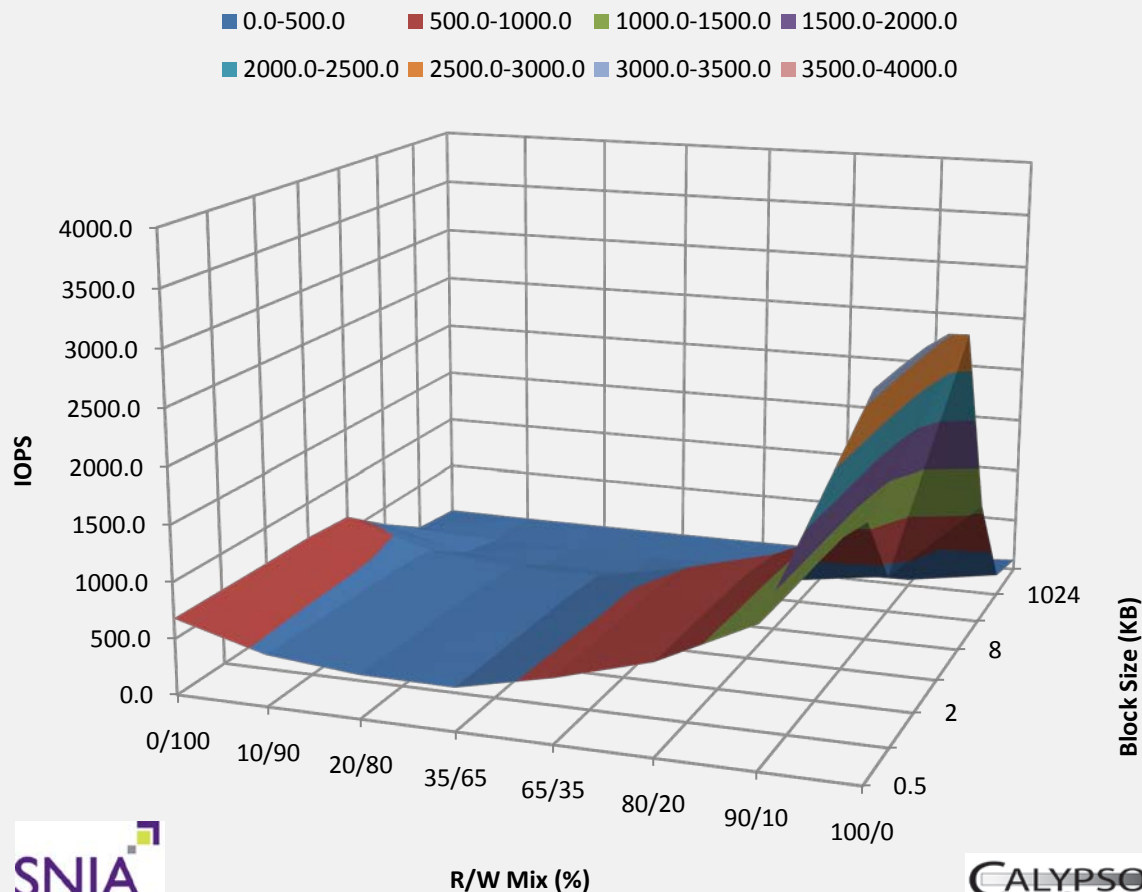


Variables influencing Performance

- Platform
 - Test Hardware (CPU, interface, chipset, etc)
 - Software (OS, drivers)
- SSS Device Architecture
 - Flash geometry, cache, flash management algorithm, etc
- Workload
 1. Write history & preconditioning: State of device before testing
 2. Workload pattern: Read/write mix, transfer size, sequential/random



3D IOPS Surface Profile



Performance
depends on

- Read/Write Mix
- Block Size
- Queue Depth
(not shown)

Note: Shown 3D IOPS image
courtesy of Calypso Systems

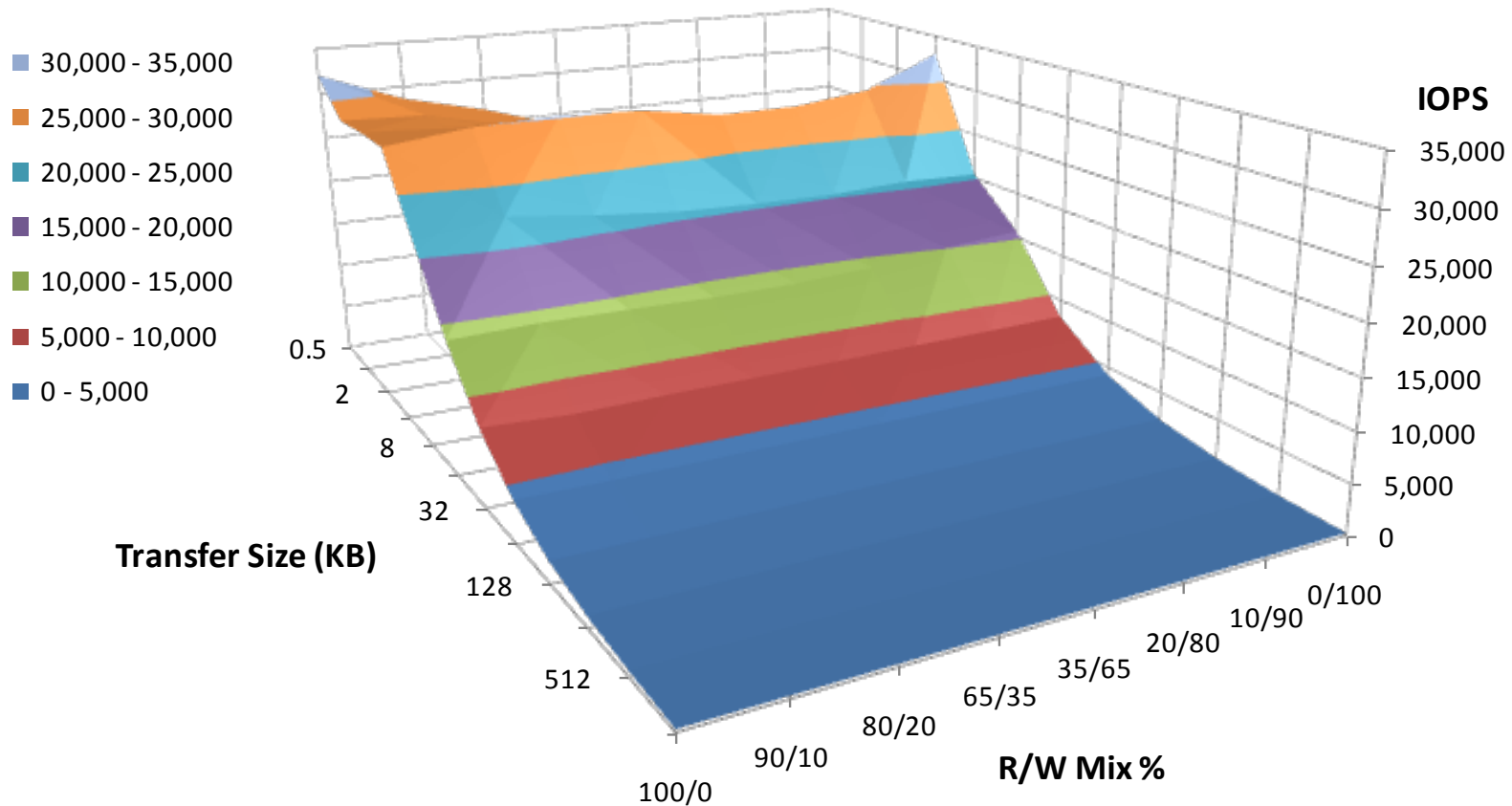
Variables influencing Performance

- Platform
 - Test Hardware (CPU, interface, chipset, etc)
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- SSS Device Architecture
 - Flash geometry, cache, flash management algorithm, etc
- Workload
 1. Write history & preconditioning: State of device before testing
 2. Workload pattern: Read/write mix, transfer size, sequential/random
 3. Data Pattern: The actual bits in the data payload written to the device



Dependency on data content - I

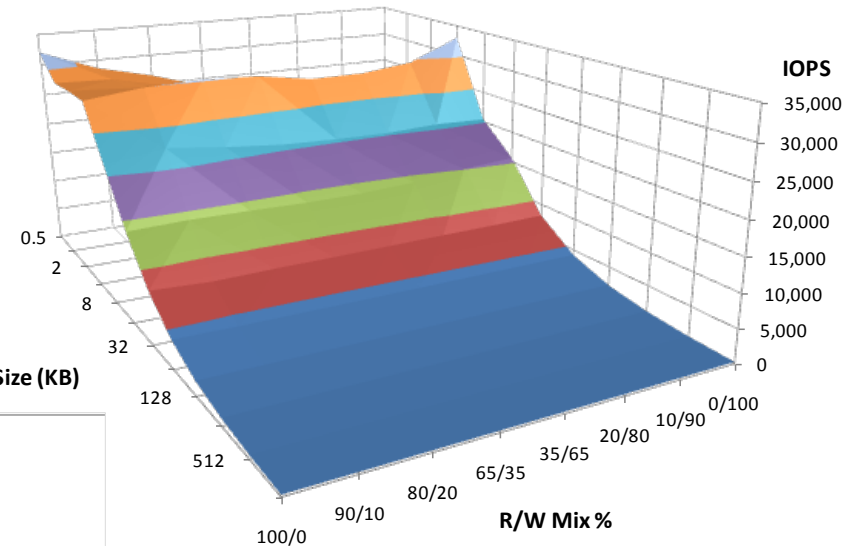
3D IOPS Surface Profile (IOMETER 2008)



Dependency on data content - 2

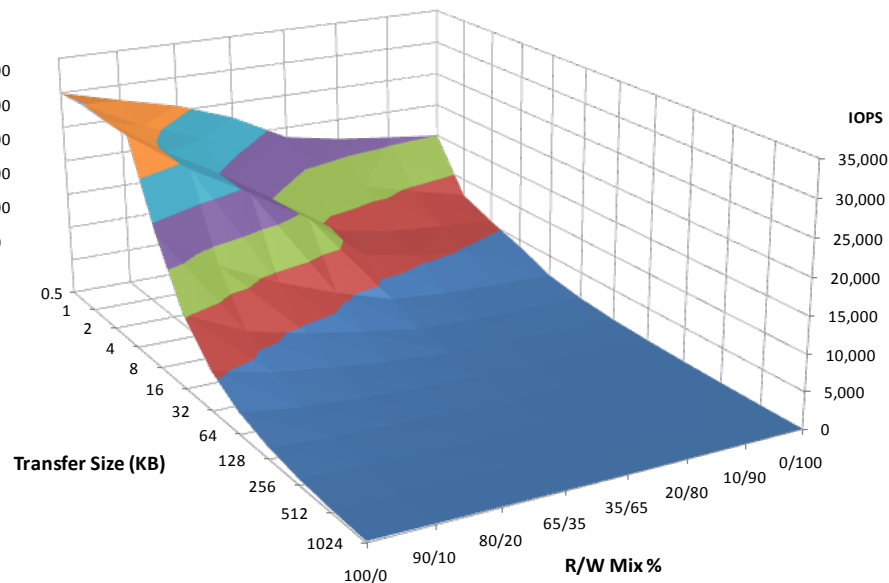
3D IOPS Surface Profile (IOMETER 2008)

- 30,000 - 35,000
- 25,000 - 30,000
- 20,000 - 25,000
- 15,000 - 20,000
- 10,000 - 15,000
- 5,000 - 10,000
- 0 - 5,000



3D IOPS Surface Profile (IOMETER 2006)

- 30,000 - 35,000
- 25,000 - 30,000
- 20,000 - 25,000
- 15,000 - 20,000
- 10,000 - 15,000
- 5,000 - 10,000
- 0 - 5,000



Benchmark Suites

	Test Suite	Client SSD	Enterprise SSD
PCMark	HDD Score, OS and application loading timing, user simulation (surfing web, windows media player, etc)	✓	
SysMark	System-level test. Measures performance based on average response time, gives score (0-250)	✓	
IOMeter	Sequential/Random performance, workload simulation (file server, web server workload, etc)	✓	✓
HDTach/ H2benchw	Performance stability, Sequential/Burst performance, Access Time	✓	✓
HD Tune	Performance stability, Sequential/Burst performance, Access Time		
Everest	Random Access Time (Read/Write)	✓	✓
VDBench	Workload generator, performance on DAS and NAS		✓
Calypso CTS	Device (RAW) level, direct IO synthetic stimulus generator for both client and enterprise	✓	✓

The Need for Industry Standardization!

- SNIA Technical Working Group (TWG)

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C

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- Future: split of test specification into separate Enterprise and Client categories



ers
effort

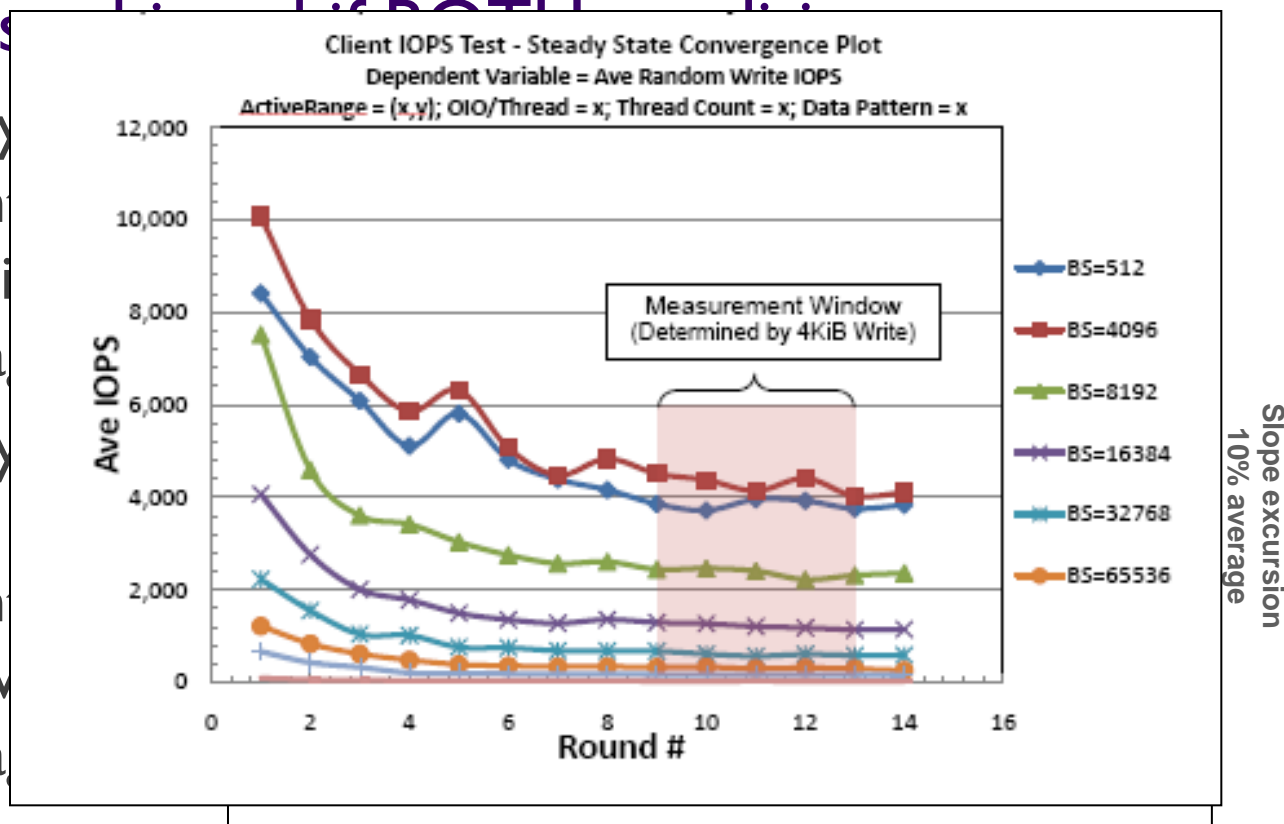
SNIA Performance Specification

1. Prepare the Device
 - ◆ Purge/Erase → put SSD back into “original” state
2. Workload independent preconditioning
 - ◆ Write data 2x capacity → bring device to known state
3. Steady State Testing (includes workload based preconditioning)
 - ◆ Run Test Loop up until steady state is achieved
 - ◆ Performance stays within $\pm 10\%$ margin
4. Test Report
 - ◆ Steady state convergence
 - ◆ Steady State Verification
 - ◆ Performance measurement (2D/3D)

- Preconditioning is key to get repeatable results
- Preconditioning needed to get drive in Steady State, after which performance can be measured

- Preconditioning is key to get repeatable results
- Preconditioning needed to get drive in Steady State, after which performance can be measured
- Two types of preconditioning
 - ◆ Workload independent – write 2x capacity with 128KB sequential writes
 - ◆ Workload dependent – run workload itself until steady state is achieved

- Measurement window is interval for last 5 measured rounds (i.e. test loops) that show steady state results
- Steady State is defined as BOTH:
 - ◆ Variation of y within measurement window is within 20% of average
 - ◆ Trending of y within measurement window is within 10% of average



Client Test

- Random IOPS
 - 100/0, 95/5, 65/35, 50/50, 35/65, 5/95, 0/100
 - 1024K, 128K, 64K, 32K, 16K, 8K, 4K, 0.5K
- Sequential MB/s
 - 100/0, 0/100
 - 1024K
- Latency (random access)
 - 100/0, 65/35, 0/100
 - 8K, 4K, 0.5K

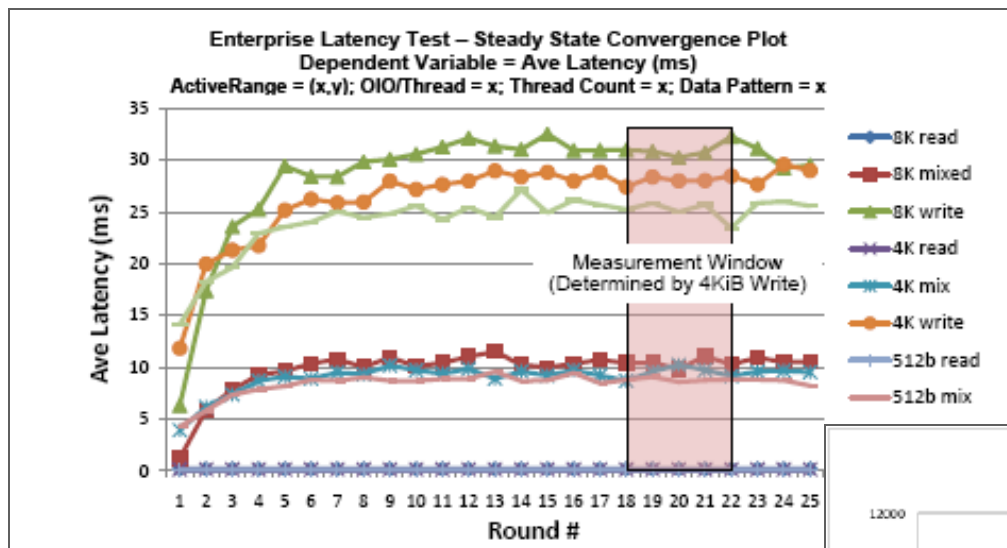
Enterprise Test

- Random IOPS
 - 100/0, 95/5, 65/35, 50/50, 35/65, 5/95, 0/100
 - 1024K, 128K, 64K, 32K, 16K, 8K, 4K, 0.5K
- Sequential MB/s
 - 100/0, 0/100
 - 1024K, 64K, 8K, 4K, 0.5K
- Latency (random access)
 - 100/0, 65/35, 0/100
 - 8K, 4K, 0.5K

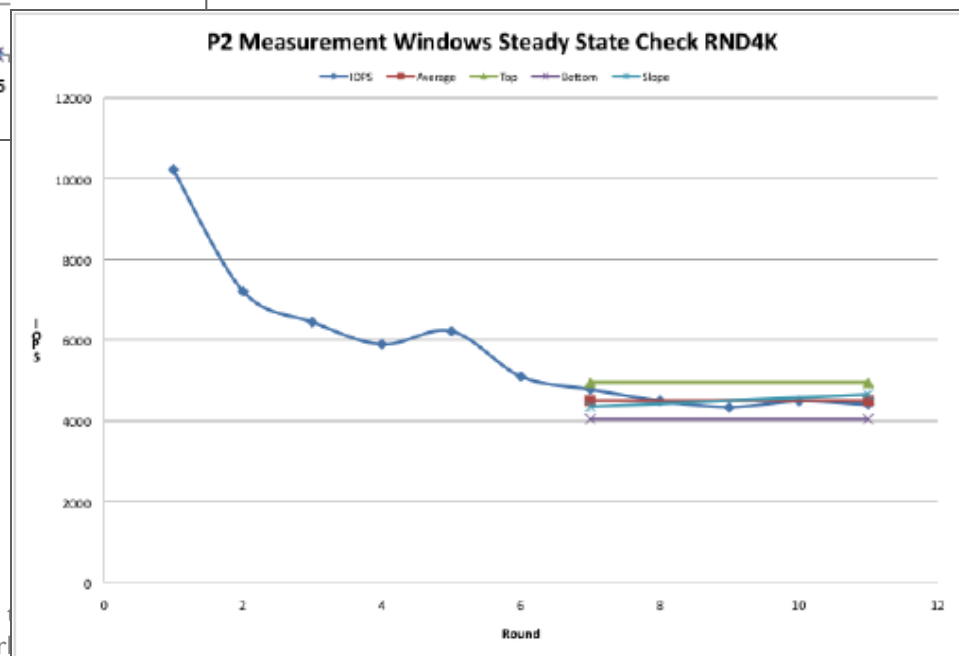
Version 1.0 will focus further on differentiating Client vs. Enterprise

Standard Reporting - 1

Steady State Convergence Plot

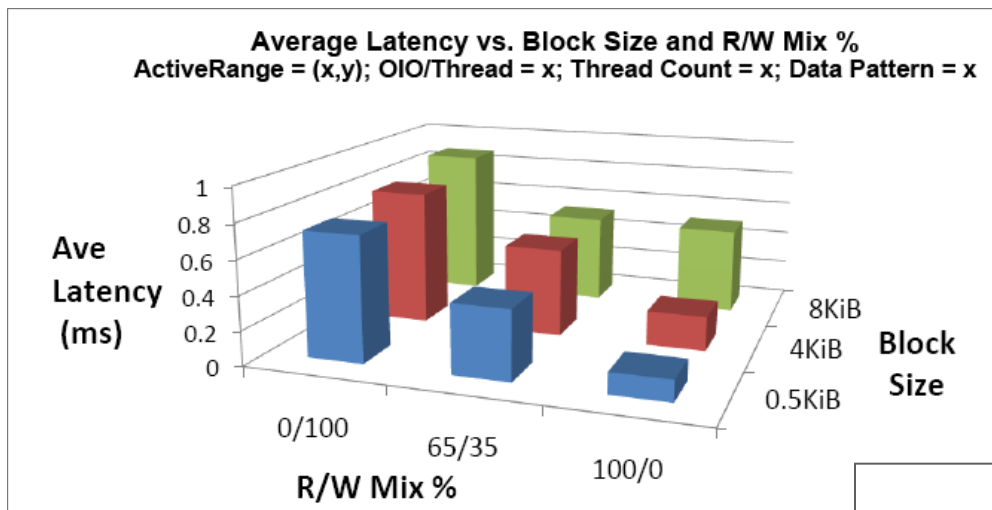


Steady State Verification

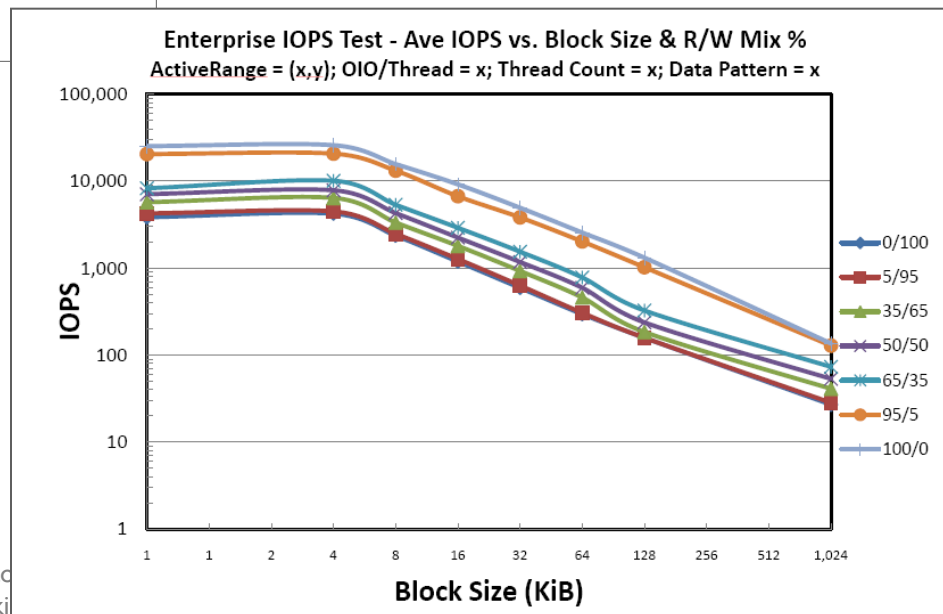


Standard Reporting - 2


Performance Measurements 3D



Performance Measurements 2D



Sample Test Report included

Informative Annex A – Sample Test Report Summary Report Page						
Solid State Storage Performance Test Specification (PTS)					Rev.	0.7
					Page 1	of 5
Device Under Test (DUT)	ABC Co.	SSS TWG PTS Summary Report		SNIA SSS TWG	 SNIA	
Model No.: Form Factor: NAND Capacity: DUT Interface:	ABC123 2.5" 256 GB MLC SATAII, SAS HBA	Test Specification: SNIA SSS TWG PTS v 0.9		Test Run Date: Report Date: Test Sponsor: Auditor Name:	Apr 3-23 2010 June 01, 2010 Calypso Systems N/A	
Testing Summary: Tests Run						
Test		Preparation			Test Loop Parameters	
		Purge Type	Workload Independent Preconditioning	Active Range %	QD / TC / OIO	Data Pattern
8.1	Client IOPS	Secure Erase	2X 128K SEQ	100%	QD 16 / TC 4 / OIO 64	RND
8.2	Client IOPS OPT – AR 10%	Secure Erase	2X 128K SEQ	10%	QD 16 / TC 4 / OIO 64	RND
8.3	Client IOPS OPT – File Data	Secure Erase	2X 128K SEQ	100%	QD 16 / TC 4 / OIO 64	NON RND File as Data Pattern
9.1	Client Throughput					
10.1	Client Latency					
General Device Description						
Device Under Test (DUT)		System Hardware Configuration		System Software Configuration		
Manufacturer	ABC Co.	System Mfr	Calypso Systems, Inc.	Operating Sys	Linux CentOS 5.4	
Model No.	ABC123	Model No.	RTP 2.0			
Serial No.	123.xxx.fff	Motherboard	Intel 5520HC	Test SW Tool(s)	Calypso CTSv6.5	
Firmware Rev No.	fff.hhhh.abc.123	Chassis	Intel SC5560DF			
User Capacity	256 GB	CPU Type	Intel 3.2GHz W5580	Other SWTool(s)		
Interface/Speed	6Gb/s SATAII	No. CPUx	Single			
Form Factor	2.5"	DRAM Type	1333MHz DDR3 ECC			
Media Type	MLC	DRAM Amt	12 GB			
Major Features:		DUT I/F	SAS HBA			
NCQ:	YES	SAS HBA	LSI 6Gb/s 9212-4a4i			
Hot Plug:	YES	SATAII	IC10HR			
Sanitize Support:	NO	PCI-e	Gen 2 (8) lane			
Other 1:		Boot HDD	160 GB 7200RPM			
Other 2:		Optical Drive				

Informative Annex A – Sample Test Report Client IOPS REQUIRED - Report Page						
Solid State Storage Performance Test Specification (PTS)				Rev.	0.7	
				Page 2	of 5	
Device Under Test (DUT)	ABC Co.	8.1 Client IOPS Test		SNIA SSS TWG	SNIA	
Key Set Up Data	DUT Preparation		Test Loop Parameters		Steady State	
DUT	256GB MLC	Purge Done:	Yes	Required:	Data Pattern	
DUT I/F	SAS HBA	Purge Type:	Security Erase		random	
Test HW	RTP 2.0	Workload Independent Preconditioning	2X 128K Sequential Wrt	Tester Choice:	OIO/Thread	
OS	CentOS 5.4				Thread Count	16
Test SW	CTSv6.5				4	
Convergence YES						
Rounds 7-11						
Active Range						
Required: 100%						
Optional: N/A						

8.1.1 Steady State Convergence Plot – All Block Sizes

Pre-conditioning Convergence Report - All Rounds

Round	64K	128K	256K	512K	1M	2M	4M	8M	16K	32K	64K
1	1000	1500	2000	3000	4000	5000	6000	7000	8000	9000	10000
2	800	1200	1600	2400	3200	4000	4800	5600	6400	7200	8000
3	700	1000	1400	2000	2800	3600	4400	5200	6000	6800	7600
4	600	900	1200	1800	2400	3200	4000	4800	5600	6400	7200
5	500	800	1000	1600	2200	3000	3800	4600	5400	6200	7000
6	400	700	900	1400	2000	2800	3600	4400	5200	6000	6800
7	300	600	800	1200	1800	2400	3200	4000	4800	5600	6400
8	200	500	700	1000	1600	2200	3000	3800	4600	5400	6200
9	100	400	600	800	1200	1800	2400	3200	4000	4800	5600
10	100	400	600	800	1200	1800	2400	3200	4000	4800	5600
11	100	400	600	800	1200	1800	2400	3200	4000	4800	5600

8.1.2 Steady State Convergence Plot – 4K Block Sizes

P1 Pre-conditioning Report - All Rounds

Round	4K
1	10000
2	7000
3	6500
4	6000
5	6200
6	5500
7	5200
8	5000
9	4800
10	5000
11	4800

- **SSSI Group of SNIA**
 - Technical Work Group (TWG) → Performance Benchmark Spec
 - Tech Dev Group → Performance Test Platform
- **JEDEC 64.8**
 - Specification for SSD endurance measurement
- **SSDA**
 - Testing of reliability (power cycling, data retention, endurance, etc) and OS compatibility (Windows 7)

- SSS Performance is dependent on many variables
- Comparing vendors is not trivial → industry standard required
- SNIA Performance Specs allows apples to apples comparison
 - Spec for review at http://www.snia.org/tech_activities/publicreview
 - Send your feedback to ssstwg@snia.org



- Please send any questions or comments on this presentation to SNIA: tracksolidstate@snia.org

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- SNIA Education Committee

**David Landsman,
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